

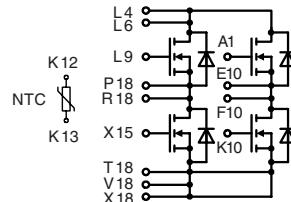
HiPerFET™ Power MOSFET

H-Bridge Topology in ECO-PAC 2

N-Channel Enhancement Mode

High dv/dt, Low t_{rr}, HDMOS™ Family

I_{D25} = 75 A
V_{DSS} = 100 V
R_{DSon} = 25 mΩ
t_{rr} ≤ 200 ns



Pin arrangement see outlines

MOSFETs

Symbol	Conditions	Maximum Ratings		
V _{DSS}	T _J = 25°C to 150°C	100		V
V _{DGR}	T _J = 25°C to 150°C; R _{GS} = 1 MΩ	100		V
V _{GS}	Continuous	±20		V
V _{GSM}	Transient	±30		V
I _{D25}	T _C = 25°C	75		A
I _{DM}	T _C = 25°C, pulse width limited by T _{JM}	300		A
I _{AR}	T _C = 25°C	75		A
E _{AR}	T _C = 25°C	30		mJ
dv/dt	I _S ≤ I _{DM} , di/dt ≤ 100 A/μs, V _{DD} ≤ V _{DSS} , T _J ≤ 150°C, R _G = 2 Ω	5		V/ns
P _D	T _C = 25°C	300		W

Symbol	Conditions	Characteristic Values		
		(T _J = 25°C, unless otherwise specified)		
		min.	typ.	max.
V _{DSS}	V _{GS} = 0 V, I _D = 250 μA	100		V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 4 mA	2.0		V
I _{GSS}	V _{GS} = ±20 V _{DC} , V _{DS} = 0		±100	nA
I _{DSS}	V _{DS} = 0.8 • V _{DSS} ; T _J = 25°C V _{GS} = 0 V; T _J = 125°C		250	μA
			1	mA
R _{DS(on)}	V _{GS} = 10 V, I _D = 0.5 I _{D25} Pulse test, t ≤ 300 μs, duty cycle d ≤ 2%		25	mΩ
g _{fs}	V _{DS} = 10 V; I _D = I _{D25} , pulse test	25	30	S
C _{iss}		4500		pF
C _{oss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz	1600		pF
C _{rss}		800		pF
t _{d(on)}		20	30	ns
t _r	V _{GS} = 10 V, V _{DS} = 0.5 • V _{DSS} , I _D = 0.5 I _{D25}	60	110	ns
t _{d(off)}	R _G = 2 Ω, (External)	80	110	ns
t _f		60	90	ns
Q _{g(on)}		180	260	nC
Q _{gs}	V _{GS} = 10 V, V _{DS} = 0.5 • V _{DSS} , I _D = 0.5 I _{D25}	36	70	nC
Q _{gd}		85	160	nC
R _{thJC}		0.5	K/W	
R _{thCK}	with heatsink compound (0.42 K/m.K; 50 μm)	0.25		K/W

Features

- HiPerFET™ technology
 - low R_{DSon}
 - low gate charge for high frequency operation
 - unclamped inductive switching (UIS) capability
 - dv/dt ruggedness
 - fast intrinsic reverse diode
- ECO-PAC 2 package
 - isolated back surface
 - enlarged creepage towards heatsink
 - application friendly pinout
 - low inductive current path
 - high reliability
 - solderable pins for PCB mounting

Applications

- drives and power supplies
- battery or fuel cell powered
- automotive, industrial vehicle etc.
- secondary side of mains power supplies

IXYS reserves the right to change limits, test conditions and dimensions.

Source-Drain Diode**Characteristic Values**(T_J = 25°C, unless otherwise specified)

Symbol	Conditions	min.	typ.	max.
I _S	V _{GS} = 0 V		75	A
I _{SM}	Repetitive;		300	A
V _{SD}	I _F = I _{D25} , V _{GS} = 0 V, Pulse test, t ≤ 300 µs, duty cycle d ≤ 2%		1.75	V
t _{rr}	I _F = 25 A, -di/dt = 100 A/µs, T _J = 25°C V _R = 25 V T _J = 125°C	300	200	ns

Temperature Sensor NTC**Characteristic Values**

min. typ. max.

R ₂₅	T = 25°C	4.75	5.0	5.25 kΩ
B _{25/50}		3375		K

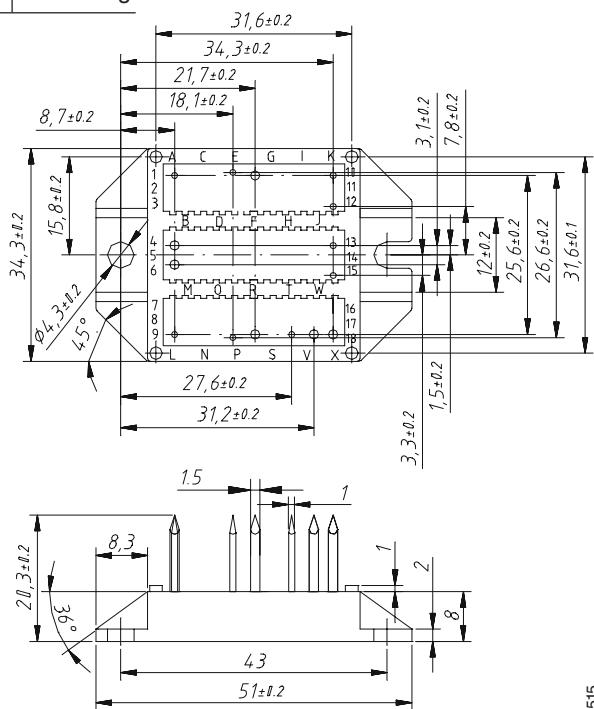
Module

Symbol	Conditions	Maximum Ratings		
		min.	typ.	max.
T _{VJ}		-40...+150		°C
T _{stg}		-40...+125		°C
V _{ISOL}	I _{ISOL} ≤ 1 mA; 50/60 Hz; t = 1 s	3600		V~
M _d	mounting torque (M4)	1.5 - 2.0		Nm
		14 - 18		lb.in.
a	Max. allowable acceleration	50		m/s ²

Symbol	Conditions	Characteristic Values		
		min.	typ.	max.
d _s	Creepage distance on surface (Pin to heatsink)	11.2		mm
d _A	Strike distance in air (Pin to heatsink)	11.2		mm

Weight		24	g

Data according to IEC 60747 refer to a single diode or transistor unless otherwise stated

Dimensions in mm (1 mm = 0.0394")

IXYS reserves the right to change limits, test conditions and dimensions.

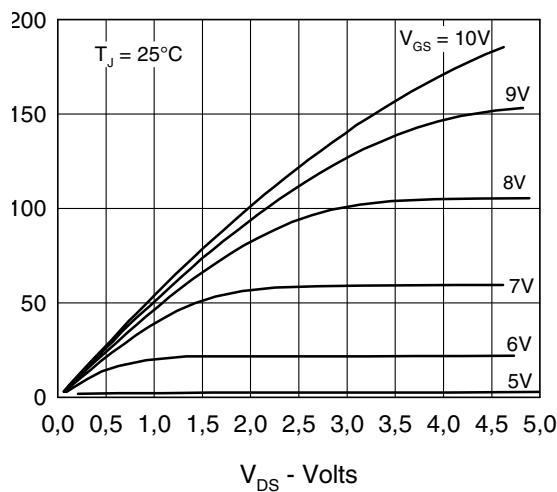


Fig. 1 Output Characteristics

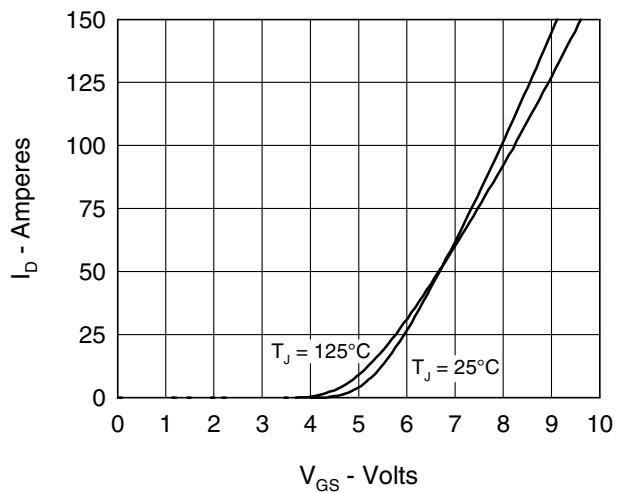


Fig. 2 Input Admittance

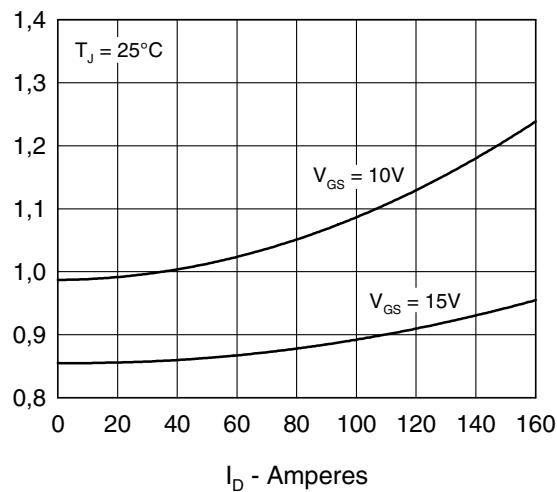
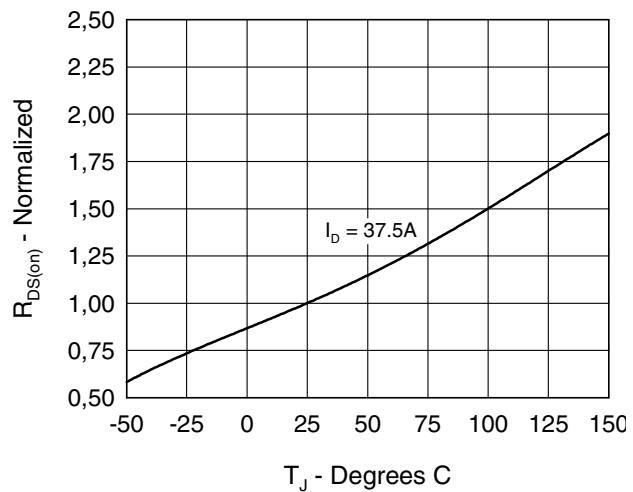
Fig. 3 $R_{DS(on)}$ vs. Drain Current

Fig. 4 Temperature Dependence of Drain to Source Resistance

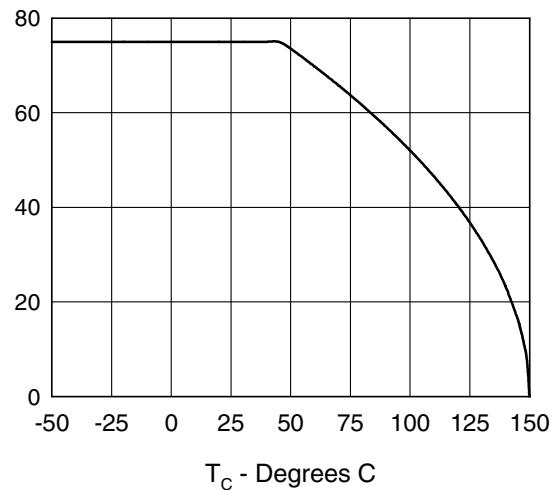


Fig. 5 Drain Current vs. Case Temperature

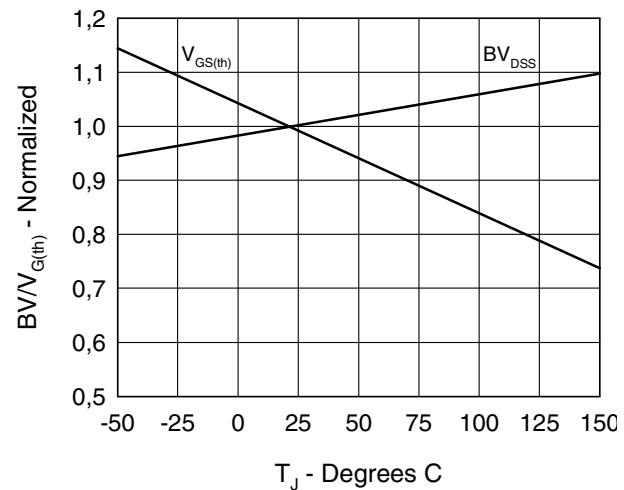


Fig. 6 Temperature Dependence of Breakdown and Threshold Voltage